EXAS RUMENTS Data sheet acquired from Harris Semiconductor SCHS104C - Revised October 2003

CMOS Hex 'D'-Type Flip-Flop

High-Voltage Types (20-Volt Rating)

CD40174B consists of six identical 'D'-type flip-flops having independent DATA inputs. The CLOCK and CLEAR inputs are common to all six units. Data is transferred to the Q outputs on the positive-going transition of the clock pulse. All six flip-flops are simultaneously reset by a low level on the CLEAR input.

The CD40174B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (VDD)
Voltages referenced to V _{SS} Terminal)
INPUT VOLTAGE RANGE, ALL INPUTS
DC INPUT CURRENT, ANY ONE INPUT ±10mA
POWER DISSIPATION PER PACKAGE (PD):
For $T_A = -55^{\circ}C$ to $+100^{\circ}C$
For T _A = +100°C to +125°C Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T _A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)
OPERATING-TEMPERATURE RANGE (T _A)
STORAGE TEMPERATURE RANGE (Tsta)

STORAGE LEAR ENAN	She holde (i sig)	
LEAD TEMPERATURE	(DURING SOLDERING):	

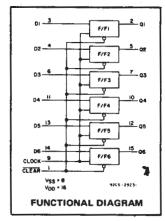
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max +265°C

Features:

- = 5-V, 10-V, and 15-V parametric rating
- Standardized symmetrical output characteristics
- = 100% tested for quiescent current at 20 V
- Maximum input current of 1 µA at 18 V
- over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range): 1 V at V_{DD} = 5 V 2 V at V_{DD} = 10 V 2.5 V at V_{DD} = 15 V

- Meets all requirements of JEDEC Tentative Standard No. 13A, "Standard Specifications for Description of 'B' Series CMOS Devices"

CD40174B Types



Applications:

- Shift Registers
- Buffer/Storage Registers
- Pattern Generators

TRUTH TABLE FOR 1 OF 6 FLIP-FLOPS

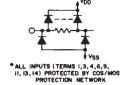
	OUTPUT		
CLOCK	DATA	CLEAR	٥
	0	1	0
	1	1	1
2	×	1	NC
X	×	0	0

1 = High Level 0 = Low Level

-09 10.12.15)

9205-2983

X = Don't Care NC = No Change





CL

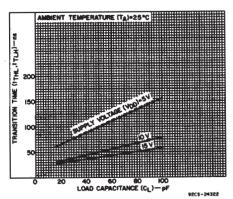
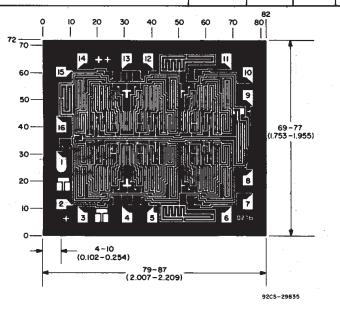
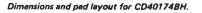


Fig. 2- Typical transition time as a function of load capacitance.

RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}C$, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V _{DD}	LIN	UNITS	
	(V)	Min.	Max.	1
Supply-Voltage Range (For T _A = Full Package-			40	
Temperature Range)		3	18	V
	5	40	-	
Data Setup Time, t _{SU}	10	20	- 1	ns
	15	10	-	
	5	80	-	
Data Hold Time, t _H	10	40	-	ns
	15	30	-	
	5	- 1	3.5	1
Clock Input Frequency, f _{CL}	10	dc	6	MHz
	15		8	
	5	· _	15	
Clock Input Rise or Fall Time, trCL, trCL	10	. –	15	μs
Clock Input Frequency, f _{CL} Clock Input Rise or Fall Time, t _r CL, t _f CL Clock Input Puise Width, t _{WL} , t _{WH}	15	-	15	
	5	130	- 1	
Clock Input Pulse Width, tWL, tWH	10	60	-	ns
	15	40	- 1	
**************************************	5	100	-	
Clear Pulse Width, twL	10	50	-	ns
•••	15	40	-	
	5	0	-	
Clear Removal Time, tREM	10	0	-	ns
	15	0	· · ·	





Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch) .

The photographs and dimensions of each CMOS chip represent a chip when it is part of the wefer. When the wafer is separated into individual chips, the angle of cleavage may vary with respect to the chip face for different chips. The actual dimensions of the isolated chip, therefore, may differ slightly from the nominal dimensions shown. The user should consider a tolerance of -3 mils 10 +16 mila applicable to the nominal dimensions shown.

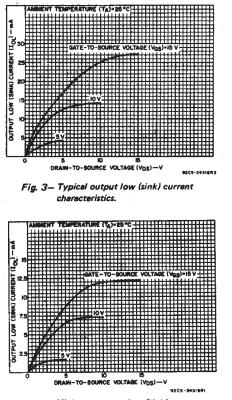
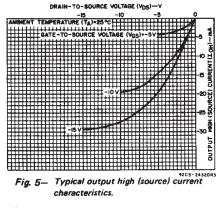
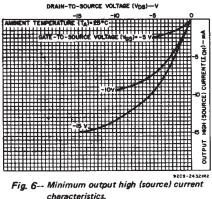


Fig. 4— Minimum output low (sink) current characteristics.

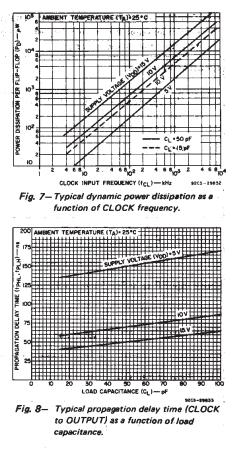


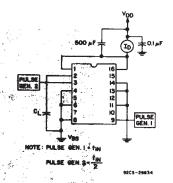


3

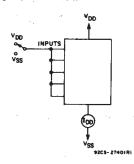
STATIC ELECTRICAL CHARACTERISTICS

CHARAC-	CONI	οιτιο	NS	LIMITS AT INDICATED TEMPERATURES (°C)							
TERISTIC	Vo	VIN	V _{DD}				a cert		+25		T
	(V)	(V)	(V)-	-55	40	+85	+125	Min.	Тур.	Max.	S
Quiescent	_	0,5	5	1	1	30	30	-	0.02	1	
Device	· _	0,10	10	2	2	60	60	-	0.02	2]μ/
Current, fDD		0,15	15	4	4	120	120	-	0.02	4	
Max.	n i n	0,20	20	20	20	600	600	-	0.04	20]
Output Low (Sink)	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-	
Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	-]
I _{OL} Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-	
Output High	4.6	0,5	5	0.64	-0.61	-0.42	-0.36	-0.51	-1]_m/
(Source)	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-]
Current,	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	2.6		
IOH Min.	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	6.8		1
Output Voltage:	- <u>-</u> 1	0,5	5		0	.05	_	0	0.05		
Low-Level,	 . :	0,10	10		0	.05		3	0.05]	
V _{OL} Max.	. 	0,15	15		0	.05	<u> </u>	0	0.05],	
Output Voltage:	— · :	0,5	5		4	.95		4.95	5	_	ľ
High-Level,	-	0,10	10		9	.95		9,95	10]
V _{OH} Min.	-	0,15	15		14	.95		14.95	15	-	
Input Low	0.5,4.5	1	5		1	.5			-	1.5	
Voltage,	1,9	_	10			3		_	-	3	
VIL Max.	1.5,13.5		15			4		-	-	4],
Inpuț High	0.5,4.5	_	5.			8.5		3.5			
Voltage,	1,9		10	7				7 °	2 . 4 .	·	
V _{IH} Min.	1.5,13.5	-	15			11		11	-	² –	
Input Current † _{IN} Max.		0,18	18	±0.1	±0.1	±1	±1	- 3	±10 ⁻⁵	±0.1	μA





Dynamic power dissipation test circuit. 當



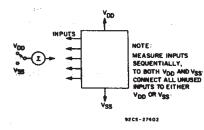
1, CL 'DD CLOCK 10% /00 DATA INPUT - 50% SULLH)* SUGHL TTLH THU /D0 90% OUTPUT -10 % *PLH - 1PHL *(LH) OR (HL) OPTIONAL REN CLEAR -50% 9203-2006984

Fig. 10- Definition of setup, hold, propagation delay, and removal times.

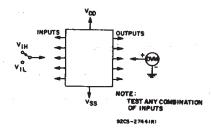
Fig. 11 - Quiescent device current test circuit.

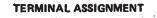
CHARACTERISTIC		TEST CONDITIONS		UNITS			
		V _{DD} (V)	Min.	Тур.	Max.		
Proposition Dalay Tim	- (5		150	300		
Propagation Delay Tim		10	_	70	140	ns .	
Clock to Output,	^t PHL ^{, t} PLH	15	_	50	100		
		5	-	100	200	<i>,</i> '	
Clear to Output,	^t PHL	10	-	50	100	ns	
		15	_	40	80	1	
		5		100	200		
Transition Time,	^t THL ^{, t} TLH	10	-	50	100	ns	
		15	_	40	80		
Minimum Pulse Width.		5	_	65	130		
Clock,	10	_	30	60	ns		
CIOCK,	^t WL ^{, t} WH	15	_	20	40		
	÷ 1.	5		50	100		
Clear,	twl	10	· · _	25	50	ns	
		15	_	20	40		
		5		20	40		
Minimum Data Setup T	10	-	10	20	ns		
	ime, t _{SU}	15	-	0	10		
		5	_	40	80		
Minimum Data Hold Ti	me, t _H	10	-	20	40	ns	
	••	15	-	15	30		
	····	5	3.5	7	_		
Maximum Clock Frequ	ency, f _{CI}	10	6	12		MHz	
·	UL	15	- 8	16			
		5 and 5	15	3 <u> </u>	1-1-1		
Maximum Clock Rise o	r Fall	10	15	· – .	- 1	μs	
Time, t _r CL, t _f CL		15	15	- **			
Input Capacitance, CIN	4						
Clear		-	_	25	40	pF	
All other		-	_	5	7.5]	
Minimum Clear Remov		5	_	-40	0		
Time,		10		15	o	ns	
1 ((11 0 ,	tREM	15	_	-10	0		

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25^{\circ}C$; Input t_p , $t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ k Ω



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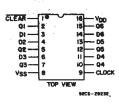




Fig. 13 - Input voltage test circuit.



24-Aug-2018

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD40174BE	ACTIVE	PDIP	Ν	16	25	Green (RoHS & no Sb/Br)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD40174BE	Samples
CD40174BEE4	ACTIVE	PDIP	Ν	16	25	Green (RoHS & no Sb/Br)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD40174BE	Samples
CD40174BF	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD40174BF	Samples
CD40174BF3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD40174BF3A	Samples
CD40174BM	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174BM	Samples
CD40174BM96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174BM	Samples
CD40174BNSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174B	Samples
CD40174BPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM0174B	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



PACKAGE OPTION ADDENDUM

24-Aug-2018

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD40174B, CD40174B-MIL :

Catalog: CD40174B

• Military: CD40174B-MIL

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com

TAPE AND REEL INFORMATION

REEL DIMENSIONS

TEXAS INSTRUMENTS





TAPE AND REEL INFORMATION

TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

*	All dimensions are nominal												
	Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
	CD40174BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
	CD40174BNSR	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1

TEXAS INSTRUMENTS

www.ti.com

PACKAGE MATERIALS INFORMATION

14-Jul-2012



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD40174BM96	SOIC	D	16	2500	333.2	345.9	28.6
CD40174BNSR	SO	NS	16	2000	367.0	367.0	38.0

J (R-GDIP-T**) 14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994. β . This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.

Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.

E. Falls within JEDEC MO-153





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- \triangle The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



4211283-4/E 08/12

D (R-PDSO-G16) PLASTIC SMALL OUTLINE Stencil Openings (Note D) Example Board Layout (Note C) –16x0,55 -14x1,27 -14x1,27 16x1,50 5,40 5.40 Example Non Soldermask Defined Pad Example Pad Geometry (See Note C) 0,60 .55 Example 1. Solder Mask Opening (See Note E) -0,07 All Around

NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



MECHANICAL DATA

PLASTIC SMALL-OUTLINE PACKAGE

0,51 0,35 ⊕0,25⊛ 1,27 8 14 0,15 NOM 5,60 8,20 5,00 7,40 \bigcirc Gage Plane ₽ 0,25 7 1 1,05 0,55 0-10 Δ 0,15 0,05 Seating Plane — 2,00 MAX 0,10PINS ** 14 16 20 24 DIM 10,50 10,50 12,90 15,30 A MAX A MIN 9,90 9,90 12,30 14,70 4040062/C 03/03

NOTES: A. All linear dimensions are in millimeters.

NS (R-PDSO-G**)

14-PINS SHOWN

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



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